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	+	AC	4	9	3	9	2	8	6	07/03/90	Brazdil et al.	558	324	†	
		AD	5	0	9	3	2	9	9	03/03/92	Suresh et al.	502	212	 	~
		AE	5	1	3	4	1	0	5	07/28/92	Paparizos et al.	502	205		
		AF	5	1	7	5	3	3	4	12/29/92	Suresh et al.	558	324	 	
		AG	5	2	1	2	1	3	7	05/18/93	Suresh et al.	502	212	†	
		AH	5	2	3	5	0	8	8	08/10/93	Paparizos et al.	558	324	 	
		AJ	5	3	6	4	8	2	5	11/15/94	Neumann et al.	502	311	 	
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		AW	5	7	8	0	6	6	4	07/14/98	Kunitoshi Aoki	558	323			
		AX	5	8	0	8	1	4	3	09/15/98	Karrer et al.	562	407	<u> </u>		
		AY	5	8	4	0	6	4	8	11/24/98	Suresh et al.	502	306			
		AZ	6	1	4	3	6	9	0	11/07/00	Komada et al.	502	211			
		BA	5	8	3	4	3	9	4	11/10/98	Chen et al.	502	302			
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LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)

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37,436

APPLICANTS
Christos Paparizos, Stephen C. Jevne, Michael J. Seely
FILING DATE
November 19, 2003

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